## Notice of References Cited Application/Control No. 10/815,106 Examiner Shin-Hon Chen Applicant(s)/Patent Under Reexamination ICHIKAWA ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0212888	11-2003	Wildish et al.	713/158
*	В	US-6,910,128	06-2005	Skibbie et al.	713/170
*	С	US-6,766,353	07-2004	Lin et al.	709/203
*	D	US-2003/0079125	04-2003	Hope et al.	713/156
*	E	US-6,993,665	01-2006	Heddings et al.	726/21
*	F	US-6,526,513	02-2003	Shrader et al.	726/4
	O	US-			
	Н	US-			
	-	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	R					
	S					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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